

RELIABILITY DATA

LT1317/1766 LT1940/41/42/43/44/45/46/47/48/49/52/56/61
 LT3010/20/23/24 LT3479/83 LT3740/50 LT3844/45

6/16/2008

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
SOIC/SOT/MSOP	1,211	9740	0732	1,645.08	0
SSOP/TSSOP	662	0233	0725	623.80	0
QFN/DFN	512	0102	0710	564.28	0
	2,385			2,833.17	0

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
QFN/DFN	72	0112	0112	138.24	0
	72			138.24	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	15,425	9812	0810	1,301.32	0
SSOP/TSSOP	11,497	0114	0807	1,481.74	0
DD PACK	100	0401	0405	2.40	0
QFN/DFN	3,552	0102	0808	647.30	0
	30,574			3,432.75	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	40,594	9812	0810	5,705.33	0
SSOP/TSSOP	11,656	9144	0807	4,679.17	0
DD PACK	150	0148	0405	15.00	0
QFN/DFN	2,949	0112	0808	743.06	0
	55,349			11,142.56	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	10,177	9812	0804	2,364.30	0
SSOP/TSSOP	11,724	9144	0752	4,392.93	0
DD PACK	100	0401	0405	10.00	0
QFN/DFN	2,895	0112	0808	847.36	0
	24,896			7,614.59	0

(1) Assumes Activation Energy = 1.0 Electron Volts
 (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 0.65 FITS
 (3) Mean Time Between Failures in Years = 175,503
 (4) Assumes 20X Acceleration from 85°C to +131°C
 Note: 1 FIT = 1 Failure in One Billion Hours.